

INTERNATIONAL STANDARD

AMENDMENT 21

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**Mechanical standardization of semiconductor devices –
Part 2: Dimensions**

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INSTRUCTIONS FOR THE INSERTION
OF NEW PAGES IN IEC 60191-2

Replace the existing title page with the new title page.

Remove the existing page 60191 IEC I containing the preface and insert in its place the new page 60191 IEC I containing the preface to Amendment 21 (2020).

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

PUBLICATION 191-2

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –

Part 2: Dimensions

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Amendment 21 (2020) to IEC 60191-2 (1966)

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –

Part 2: Dimensions

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PREFACE TO AMENDMENT 21 (2020)

This amendment has been prepared by subcommittee 47D: Semiconductor devices packaging, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

CDV	Report on voting
47D/899/CDV	47D/907/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

CHAPTER I – DEVICE OUTLINE DRAWINGS

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